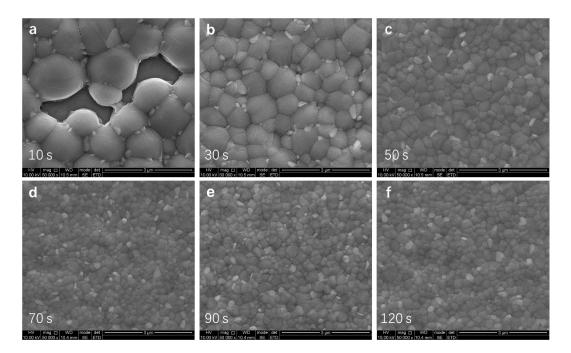
## Supplementary Materials for

## High-temperature inverted annealing for efficient perovskite photovoltaics

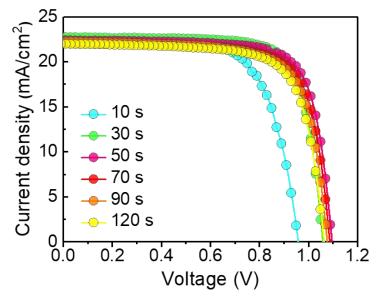
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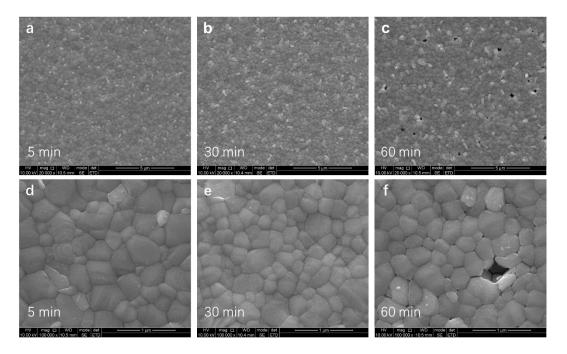
**Fig. S1.** Top-view SEM images of the CsFAMA hybrid perovskite films with respect to pre-annealing time at 60°C. (a) 10 s, (b) 30 s, (c) 50 s, (d) 70 s, (e) 90 s, (f) 120 s.



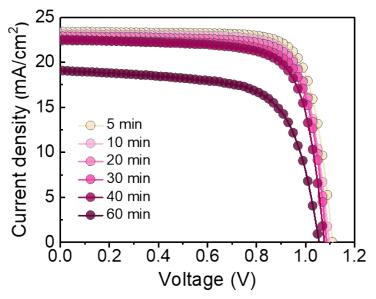
**Fig. S2.** Representative *J*-*V* curves of cells based on CsFAMA films with different pre-annealing time. Note that these *J*-*V* curves were recorded under reverse scan direction with a scan rate of 0.1 V/s.

conditions	$V_{\rm OC}$ (V)	$J_{ m SC}~({ m mA/cm^2})$	FF (%)	PCE (%)
10 s	0.958	22.89	69.2	15.11
30 s	1.058	23.12	76.5	18.71
50 s	1.096	22.74	76.3	19.02
70 s	1.087	22.46	74.4	18.17
90 s	1.071	22.34	73.7	17.63
120 s	1.064	22.36	73.0	17.37

**Table S1.** Summary of photovoltaic metrics data of each kind of cell derived from the *J*-*V* curves in Figure S2.



**Fig. S3.** Top-view SEM images of the CsFAMA triple-cation perovskite films treated by inverted annealing at 150°C for different periods of time. (a, d) 5 min, (b, e) 30 min, (c, f) 60 min.



**Fig. S4.** Representative *J-V* curves of cells based on CsFAMA perovskite films treated by inverted annealing at  $150^{\circ}$ C for different periods of time. Note that these *J-V* curves were measured under reverse scan direction with a sweep rate of 0.1 V/s.

**Table S2.** Summary of photovoltaic metrics data of each kind of device derived from the *J*-*V* curves in Figure S4.

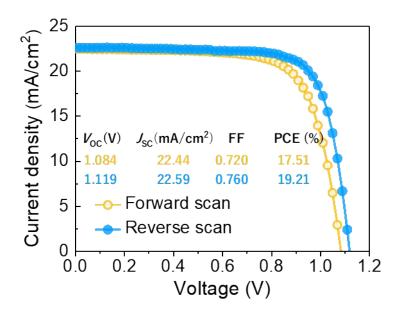
conditions	$V_{\rm OC}({ m V})$	$J_{\rm SC}~({\rm mA/cm^2})$	FF (%)	PCE (%)
5 min	1.110	23.37	77.7	20.16
10 min	1.097	23.06	77.0	19.48
20 min	1.087	22.85	77.4	19.22
30 min	1.085	22.40	76.3	18.55
40 min	1.076	22.06	74.1	17.59
60 min	1.063	18.69	67.7	13.45

conditions	diffraction peak	FWHM (degree)	intensity (counts)	
	(001)	0.136	3072	
:	(002)	0.102	2248	
inverted	(012)	0.097	2160	
	(001) of PbI <sub>2</sub>	/	444	
	(001)	0.130	2789	
,	(002)	0.106	1944	
normal	(012)	0.097	2109	
	(001) of PbI <sub>2</sub>	/	565	

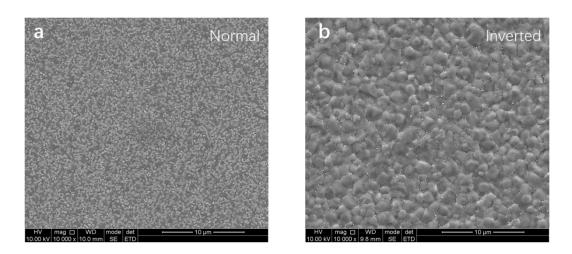
peaks for the CsFAMA perovskite films based on the XRD data shown in Figure 3d.

**Table S4.** Fitting results of the TRPL decay curves for CsFAMA perovskite films prepared on glass substrates.

conditions for CsFAMA films	$\tau_1$ (ns)	Fraction 1	$\tau_2$ (ns)	Fraction 2	$\tau_{ave} \left( ns \right)$
Normal annealing	4.9	4.1%	173.1	95.9%	172.9
Inverted annealing	4.2	2.6%	235.1	97.4%	235.0



**Fig. S5.** J-V curves of the best-performing cell based on a normal annealed CsFAMA perovskite film measured from reverse and forward scan with a sweep rate of 0.1 V/s.



**Fig. S6.** Surface-view SEM images of MAPbI<sub>3</sub> perovskite films treated by normal annealing (a) or inverted annealing (b) at 150°C for 5 min.

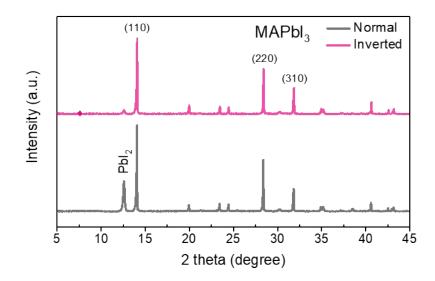
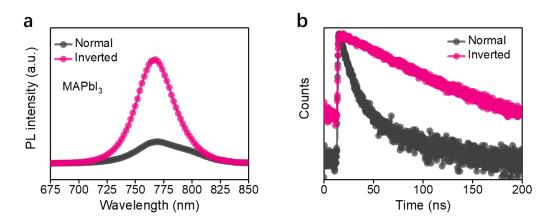


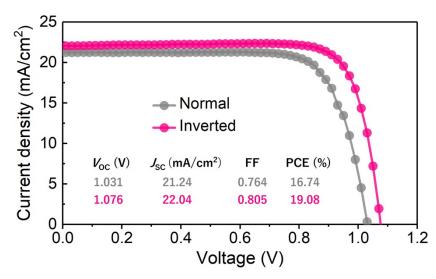
Fig. S7. XRD patterns of normal annealed and inverted annealed MAPbI<sub>3</sub> perovskite films.



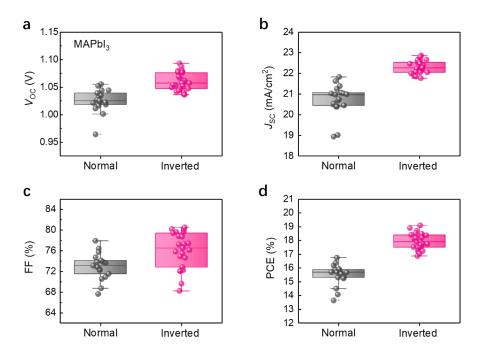
**Fig. S8.** Steady-state PL spectra (a) and TRPL decay curves (b) of the two types of MAPbI<sub>3</sub> perovskite films deposited on glass substrates.

conditions for MAPbI <sub>3</sub> films	$\tau_1$ (ns)	Fraction 1	$ au_2$ (ns)	Fraction 2	$\tau_{\rm ave}({\rm ns})$
Normal annealing	8.3	59.0%	46.9	41.0%	39.1
Inverted annealing	14.0	9.6%	70.6	90.4%	69.4

Table S5. Fitting results of the TRPL decay curves for  $MAPbI_3$  films prepared on glass substrates.



**Fig. S9.** *J*-*V* curves of the best-performing photovoltaic device based on the normal annealed or inverted annealed MAPbI<sub>3</sub> perovskite films. Note that the *J*-*V* curves were recorded under reverse scan with a scan rate of 0.1 V/s.



**Fig. S10.** Statistical distributions of photovoltaic metrics collected from around 20 independent cells of the two types of MAPbI<sub>3</sub> photovoltaic devices. (a)  $V_{OC}$ , (b)  $J_{SC}$ , (c) FF, (d) PCE.

**Table S6.** Summary of the photovoltaic metrics collected from around 20 independent cells of the two types of MAPbI<sub>3</sub> perovskite photovoltaic devices.

devices	$V_{\rm OC}$ (V)	$J_{ m SC}~({ m mA/cm^2})$	FF (%)	PCE (%)
Normal	$1.025 \pm 0.021$	20.72±0.75	72.9±2.5	15.48±0.77
Inverted	$1.060 \pm 0.016$	22.30±0.30	76.0±3.4	17.93±0.58